

Search Notes

Application/Control No.

10/782,470

Examiner

Randall Chin

Applicant(s)/Patent under
Reexamination

FORCEN, LUIS

Art Unit

1744

SEARCHED

Class	Subclass	Date	Examiner
15	104.001		
15	104.94		
15	210.1		
15	244.1		
184	99		
184	100		
184	101		
184	102	6/27/2005	RC

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventor name search	6/27/2005	RC